

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination PEREZ ET AL.	
		Examiner Bernard E Souw	Art Unit 2881	Page 1 of 1

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*	B	US-6,635,871	10-2003	Xu et al.	250/306
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*	E	US-5,159,195	10-1992	Van House, James C.	250/309
*	F	US-4,864,131	09-1989	Rich et al.	250/308
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NON-PATENT DOCUMENTS

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*	U	"The LLNL Electron-Positron Beam Facility", http://www-pat.llnl.gov/H-Div/Positrons/PositronFacility.html
*	V	van Veen et al., Appl. Surf. Dci. 116 (1997) 39-44
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*	X	Baier et al., Phys. Rev. ST Accel. Beans 5, 121001 (2002)

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.